Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.		
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APPLICANT							
LIST OF	REFER	ENCES CITED BY API	PLICANT	Stephane POCAS, et al.			
				FILING DATE		GROUP	
				June 22, 2006		2892	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW Hartmut BRACHT, "DIFFUSION MECHANISMS AND INTRINSIC POINT-DEFECT PROPERTIES IN SILICON", www.mrs.org/publications/bulletin, MRS Bulletin/June 2000, pages 22-27.							
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Examiner	1				Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							